

**IEEE 1687 compliant ecosystem for embedded instrumentation access and in-field health monitoring**

**Tšertov, Anton**; Jutman, Artur; Shibin, Konstantin; **Devadze, Sergei** IEEE AUTOTESTCON 2018 : National Harbor, September 17-20, 2018 : proceedings 2018 / 9 p.: ill <https://doi.org/10.1109/AUTEST.2018.8532559>

**In-field detection of degradation on PCB assembly high-speed buses**

**Odintsov, Sergei** IEEE AUTOTESTCON 2018 : National Harbor, September 17-20, 2018 : proceedings 2018 / 6 p.: ill <https://doi.org/10.1109/AUTEST.2018.8532547>